

## **STW9N150**

## N-channel 1500V - 2.2Ω - 8A - TO-247 Very high voltage PowerMESH™ Power MOSFET

TARGET SPECIFICATION

### **General features**

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	Pw
STW9N150	1500V	< 2.7Ω	8A	350W

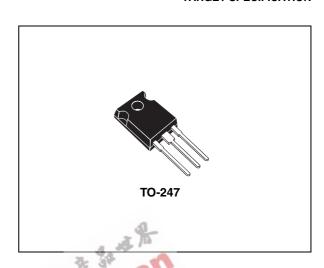
- 100% avalanche tested
- Avalanche ruggedness
- Gate charge minimized
- Very low intrinsic capacitances
- High speed switching
- Very low on-resistance



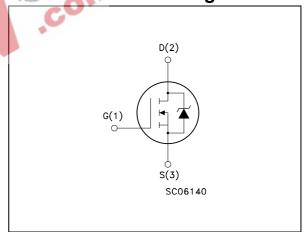
Using the well consolidated high voltage MESH OVERLAY™ process, STMicroelectronics has designed an advanced family of Power MOSFETs with outstanding performances. The strengthened layout coupled with the Company's proprietary edge termination structure, gives the lowest R<sub>DS(on)</sub> per area, unrivalled gate charge and switching characteristics.

### **Applications**

■ Switching application



## Internal schematic diagram



### Order code

Part number	Marking	Package	Packaging
STW9N150	W9N150V	TO-247	Tube

**Electrical ratings** STW9N150

#### **Electrical ratings** 1

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	1500	٧
V <sub>GS</sub>	Gate- source voltage	± 30	٧
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25°C	8	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100°C	5	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	32	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25°C	350	W
	Derating factor	0.37	W/°C
T <sub>j</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature -55 to 150		°C

<sup>1.</sup> Pulse width limited by safe operating area

Table 2. Thermal data

Table 2.	Thermal data	and the	
Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	0.36	°C/W
Rthj-amb	Thermal resistance junction-ambient max	62.5	°C/W

**Avalanche characteristics** Table 3.

Symbol	Parameter	Max value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by T <sub>j</sub> max)	Tbd	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	Tbd	mJ

## 2 Electrical characteristics

(Tcase =25°C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 1$ mA, $V_{GS} = 0$	1500			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	$V_{DS}$ = Max rating $V_{DS}$ = Max rating, $T_{C}$ =125°C			10 500	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 30V			± 100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R <sub>DS(on</sub>	Static drain-source on resistance	$V_{GS} = 10V, I_D = 1.3A$		2.2	2.7	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	$V_{DS} = 30V$ , $I_D = 2A$		Tbd		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$		3600 280 35		pF pF pF
R <sub>g</sub>	Gate input resistance	f=1MHz Gate DC Bias=0 Test signal level=20mV open drain		2		Ω
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD}$ = 600V, $I_{D}$ = 2.5A, $V_{GS}$ = 10V (see Figure 2)		90 Tbd Tbd		nC nC nC

<sup>1.</sup> Pulsed: Pulse duration = 300 μs, duty cycle 1.5%

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STW9N150 **Electrical characteristics** 

Table 6. **Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
$\begin{array}{c} t_{d(on)} \\ t_{r} \\ t_{d(off)} \\ t_{f} \end{array}$	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD}$ = 750V, $I_D$ = 2A, $R_G$ = 4.7 $\Omega$ , $V_{GS}$ = 10V (see Figure 1)		Tbd Tbd Tbd Tbd		ns ns ns ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current				8	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)				32	Α
V <sub>SD</sub> (2)	Forward on voltage	I <sub>SD</sub> = 4A, V <sub>GS</sub> = 0			Tbd	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 4A, di/dt = 100A/μs		Tbd		ns
$Q_{rr}$	Reverse recovery charge	V <sub>DD</sub> = 45V Tj = 25°C		Tbd		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 3)		Tbd		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 4A, di/dt = 100A/μs		Tbd		ns
$Q_{rr}$	Reverse recovery charge	V <sub>DD</sub> = 45V Tj = 150°C		Tbd		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 3)		Tbd		Α
1. Pulse wi	dth limited by safe operating area	20 3				
2. Pulsed: p	oulse duration = 300µs, duty cycle 1.	5%				

STW9N150 Test circuits

## 3 Test circuits

Figure 1. Switching times test circuit for resistive load

Figure 2. Gate charge test circuit

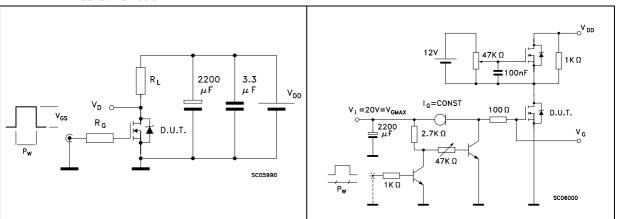


Figure 3. Test circuit for inductive load switching and diode recovery times

Figure 4. Unclamped Inductive load test circuit

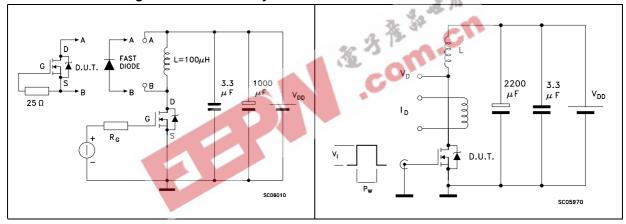
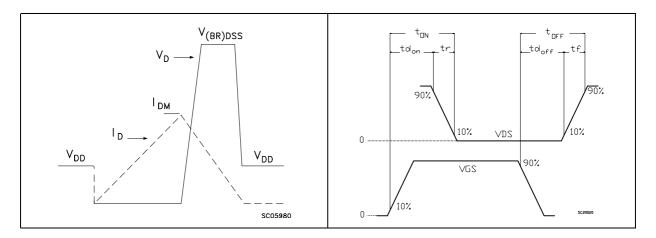


Figure 5. Unclamped inductive waveform

Figure 6. Switching time waveform



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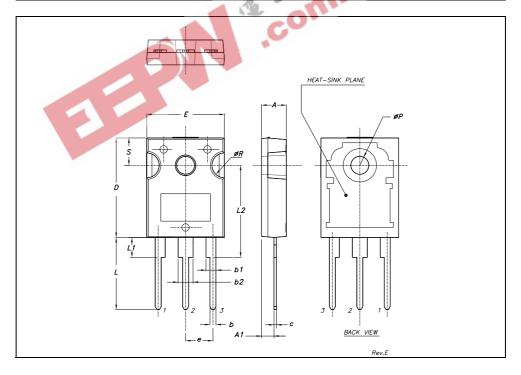
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: <a href="https://www.st.com">www.st.com</a>



### **TO-247 MECHANICAL DATA**

DIM.		mm.			inch	
DIIVI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
С	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
Е	15.45		15.75	0.608		0.620
е		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50		2 %	0.728	
øΡ	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50	20 %		0.216	



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Revision history STW9N150

# 5 Revision history

Table 8. Revision history

Date	Revision	Changes
24-May-2007	1	First release



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